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Tue, 23 May 2006, 2:21:53 PM EST

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- #2 (substrate<sentence>coupling and substrate<sentence>noise and substrate<sentence>model* and matrix<IN>metadata)
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- #5 (substrate<sentence>coupling and substrate<sentence>noise and substrate<sentence>model* and matrix<IN>metadata)
- #6 (substrate<sentence>coupling<sentence>noise)<paragraph>model* and (scalable<sentence>parameter?)
- #Z (substrate<sentence>coupling<sentence>noise)<paragraph>model* and (scalable<sentence>parameter?)
- #8 (substrate<sentence>coupling<sentence>noise)<paragraph>model* and (scalable<sentence>parameter?)



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Digital Object Identifier 10.1109/RFIC.2004.1320694

AbstractPlus | Full Text: PDF(381 KB) | IEEE CNF

Radio Frequency Integrated Circuits (RFIC) Symposium, 2004, Digest of Papers, 2004 IEEE

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	 An automated and efficient substrate noise analysis tool Hongmei Li; Zemke, C.E.; Manetas, G.; Okhmatovski, V.I.; Rosenbaum, E.; Cangellaris, A.C.; <u>Computer-Aided Design of Integrated Circuits and Systems. IEEE Transactions on</u> Volume 25, Issue 3, March 2006 Page(s):454 - 468 <u>Digital Object Identifier 10.1109/TCAD.2005.854628</u>
	AbstractPlus Full Text: PDF(800 KB) IEEE JNL Rights and Permissions
G	 Stable and efficient reduction of large, multiport RC networks by pole analysis via congruen Kerns, K.J.; Yang, A.T.; Computer-Aided Design of Integrated Circuits and Systems, IEEE Transactions on Volume 16, Issue 7, July 1997 Page(s):734 - 744 Digital Object Identifier 10.1109/43.644034 AbstractPlus References Full Text: PDF(372 KB) IEEE JNL Rights and Permissions
	8. Numerically stable Green function for modeling and analysis of substrate coupling in integr. Niknejad, A.M.; Gharpurey, R.; Meyer, R.G.; Computer-Aided Design of Integrated Circuits and Systems, IEEE Transactions on Volume 17, Issue 4, April 1998 Page(s):305 - 315 Digital Object Identifier 10.1109/43.703820 AbstractPlus References Full Text: PDF(400 KB) IEEE JNL
	Rights and Permissions
	 Efficient techniques for accurate modeling and simulation of substrate coupling in mixed-si. Costa, J.P.; Mike Chou; Silveira, L.M.; Computer-Aided Design of Integrated Circuits and Systems. IEEE Transactions on Volume 18, Issue 5, May 1999 Page(s):597 - 607 Digital Object Identifier 10.1109/43.759076
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	12. Block structure preserving model order reduction Hao Yu; Lei He; Tar, S.X.D.; <u>Behavioral Modeling and Simulation Workshop, 2005, BMAS 2005, Proceedings of the 2005 IEEE</u> 22-23 Sept. 2005 Page(s):1 - 6 Digital Object Identifier 10.1109/BMAS.2005.1518178
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14. Isolation strategy against substrate coupling in CMOS mixed-signal/RF circuits Kosaka, D.; Nagata, M.; Hiraoka, Y.; Imanishi, I.; Maeda, M.; Murasaka, Y.; Iwata, A.; VLSI Circuits, 2005. Digest of Technical Papers. 2005 Symposium on 16-18 June 2005 Page(s):276 - 279 Digital Object Identifier 10.1109/VLSIC.2005.1469385 AbstractPlus Full Text: PDF(871 KB) IEEE CNF Rights and Permissions
15. HSpeedEx: a high-speed extractor for substrate noise analysis in complex mixed-signal SOt Koukab, A.; Dehollain, C.; Declercq, M.; Design Automation Conference, 2002, Proceedings, 39th 10-14 June 2002 Page(s):767 - 770 Digital Object Identifier 10.1109/DAC.2002.1012726 AbstractPlus Full Text: PDF(564 KB) IEEE CNF Rights and Permissions
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17. Characterization of SSN Coupling to Signal VIa In Multi-layer PCBs and Packages Jongbae Park; Hyungsoo Kim; Jun So Pak; Joungho Kim; Electromagnetic Compatibility. 2006. EMC-Zurich 2006. 17th International Zurich Symposium on 27-03 Feb. 2006 Page(s):328 - 331 AbstractPlus Full Text: PDF(264 KB) IEEE CNF Rights and Permissions
18. Synthesized compact models (SCM) of substrate noise coupling analysis and synthesis in n Lan, H.; Dutton, R.; Design. Automation and Test in Europe Conference and Exhibition. 2004. Proceedings Volume 2, 16-20 Feb. 2004 Page(s):836 - 841 Vol.2 Digital Object Identifier 10.1109/DATE.2004.1268987 AbstractPlus Full Text: PDF(618 KB) IEEE CNF Rights and Permissions
19. SuPREME: substrate and power-delivery reluctance-enhanced macromodel evaluation Tsung-Hao Chen; Luk, C.; Chen, C.CP.; Computer Aided Design, 2003. ICCAD-2003. International Conference on 9-13 Nov. 2003 Page(s):786 - 792 Digital Object Identifier 10.1109/ICCAD.2003.1257898 AbstractPlus Full Text: PDE(550 KB) IEEE CNF Rights and Permissions
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		Singh, R.; Tretiakov, Y.V Harame, D.L.; <u>Electron Devices, IEEE 1</u> Volume 50, Issue 3, Ma	.; Johnson, J.B.; Sweeney, S	ced RF/mixed-signal silicon go S.L.; Barry, R.L.; Kumar, M.; Ertu	

AbstractPlus | References | Full Text: PDF(1646 KB) | IEEE JNL Rights and Permissions 6. Accurate modeling and parameter extraction for meander-line N-well resistors Murji, R.; Deen, M.J.; Electron Devices, IEEE Transactions on Volume 52, Issue 7, July 2005 Page(s):1364 - 1369 Digital Object Identifier 10.1109/TED.2005.850637 AbstractPlus | Full Text: PDF(360 KB) IEEE JNL Rights and Permissions 7. Simulation and measurement of supply and substrate noise in mixed-signal ICs Owens, B.E.; Adluri, S.; Birrer, P.; Shreeve, R.; Arunachalam, S.K.; Mayaram, K.; Fiez, T.S.; Solid-State Circuits, IEEE Journal of Volume 40, Issue 2, Feb. 2005 Page(s):382 - 391 Digital Object Identifier 10.1109/JSSC.2004.841039 AbstractPlus | References | Full Text: PDF(1024 KB) | IEEE JNL Rights and Permissions 8. CAD tools for embedded analogue circuits in mixed-signal integrated systems on chip Gielen, G.G.E.; Computers and Digital Techniques, IEE Proceedings-Volume 152, Issue 3, 6 May 2005 Page(s):317 - 332 Digital Object Identifier 10.1049/ip-cdt:20045116 AbstractPlus | Full Text: PDF(931 KB) | IEE JNL 9. An efficient modeling approach for substrate noise coupling analysis Ozis, D.; Mayaram, K.; Fiez, T.; Circuits and Systems, 2002, ISCAS 2002, IEEE International Symposium on Volume 5, 26-29 May 2002 Page(s):V-237 - V-240 vol.5 Digital Object Identifier 10.1109/ISCAS.2002.1010684 AbstractPlus | Full Text: PDF(465 KB) IEEE CNF Rights and Permissions 10. A comprehensive geometry-dependent macromodel for substrate noise coupling in heavily processes Ozis, D.; Fiez, T.; Mayaram, K.; Custom Integrated Circuits Conference, 2002, Proceedings of the IEEE 2002 12-15 May 2002 Page(s):497 - 500 Digital Object Identifier 10.1109/CICC.2002.1012887 AbstractPlus | Full Text: PDF(451 KB) | IEEE CNF Rights and Permissions 11. Design procedure for fully integrated 900 MHz medium power amplifiers in 0.6 µm CMOS tec resistant epi-substrate Baureis, P.; Peter, M.; Hein, H.; Oehler, F.; Silicon Monolithic Integrated Circuits in RF Systems, 2001. Digest of Papers, 2001 Topical Meeting 12-14 Sept. 2001 Page(s):142 - 148 Digital Object Identifier 10.1109/SMIC.2001.942356 AbstractPlus | Full Text: PDF(2088 KB) IEEE CNF Rights and Permissions

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	L8	L4 and (model\$ with substrate)	12
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	L6	L4 and scalable and parameter?	4
	L5	L4 and (scalable same parameter?)	1
	L4	L3 and matrix	60
	L3	L2 and (substrate with coupling with noise)	653
	L2	(substrate with coupling) and (substrate with noise)	1475
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L1: Entry 1 of 1

File: PGPB

Jun 17, 2004

PGPUB-DOCUMENT-NUMBER: 20040117162

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20040117162 A1

TITLE: Modeling substrate noise coupling using scalable parameters

PUBLICATION-DATE: June 17, 2004

INVENTOR-INFORMATION:

NAME CITY STATE COUNTRY Ozis, Dicle Seattle WA US Mayaram, Kartikeya Corvallis OR US Fiez, Terri Corvallis US OR

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L5: Entry 1 of 1

File: PGPB

Jun 17, 2004

PGPUB-DOCUMENT-NUMBER: 20040117162

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20040117162 A1

TITLE: Modeling substrate noise coupling using scalable parameters

PUBLICATION-DATE: June 17, 2004

INVENTOR-INFORMATION:

NAME CITY STATE COUNTRY Ozis, Dicle Seattle WA US Mayaram, Kartikeya Corvallis OR US Fiez, Terri Corvallis OR US

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L6: Entry 1 of 4

File: PGPB

Nov 17, 2005

PGPUB-DOCUMENT-NUMBER: 20050254106

PGPUB-FILING-TYPE: corrected

DOCUMENT-IDENTIFIER: US 20050254106 A9

TITLE: Scanning device for coded data

PUBLICATION-DATE: November 17, 2005

PRIOR-PUBLICATION:

DOC-ID DATE

US 0190092 A1 September 30, 2004

INVENTOR-INFORMATION:

NAME	CITY	STATE	COUNTRY
Silverbrook, Kia	Balmain		AU
Lapstun, Paul	Balmain		AU
Rusman, Jan	Balmain		AU
Henderson, Peter Charles Boyd	Balmain		AU
Moini, Alireza	Balmain		AU
Yourlo, Zhenya Alexander	Balmain		AU
Underwood, Matthew John	Balmain		AU
Ridley, Nicholas Damon	Balmain		AU

US-CL-CURRENT: <u>358/539</u>; <u>358/474</u>

	Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Draw C

L6: Entry 2 of 4 File: PGPB Sep 30, 2004

PGPUB-DOCUMENT-NUMBER: 20040190092

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20040190092 A1

TITLE: Scanning device for coded data

Record List Display Page 2 of 3

PUBLICATION-DATE: September 30, 2004

INVENTOR-INFORMATION:

NAME CITY STATE COUNTRY Silverbrook, Kia Balmain ΑU Lapstun, Paul Balmain ΑU Rusman, Jan Balmain ΑU Henderson, Peter Charles Boyd Balmain ΑU Moini, Alireza Balmain ΑU Yourlo, Zhenya Alexander Balmain AU Underwood, Matthew John Balmain ΑU Ridley, Nicholas Damon Balmain ΑU

US-CL-CURRENT: 358/539; 358/474

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Draw, De

☐ 3. Document ID: US 20040190085 A1

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File: PGPB

Sep 30, 2004

PGPUB-DOCUMENT-NUMBER: 20040190085

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20040190085 A1

TITLE: Sensing device for coded data

PUBLICATION-DATE: September 30, 2004

INVENTOR-INFORMATION:

NAME CITY STATE COUNTRY Silverbrook, Kia Balmain ΑU Lapstun, Paul Balmain ΑU Henderson, Peter Charles Boyd Blamain AU Moini, Alireza Balmain ΑU Yourlo, Zhenya Alexander Balmain ΑU Underwood, Matthew John Balmain ΑU Ridley, Nicholas Damon Balmain ΑU Rusman, Jan Balmain AU

US-CL-CURRENT: <u>358/474</u>; <u>358/539</u>

☐ 4. Document ID: US 20040117162 A1

L6: Entry 4 of 4 File: PGPB

Jun 17, 2004

PGPUB-DOCUMENT-NUMBER: 20040117162

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PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20040117162 A1

TITLE: Modeling substrate noise coupling using scalable parameters

PUBLICATION-DATE: June 17, 2004

INVENTOR-INFORMATION:

NAME CITY STATE COUNTRY Ozis, Dicle Seattle WA US Mayaram, Kartikeya Corvallis OR US Fiez, Terri Corvallis OR US

US-CL-CURRENT: 703/2

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L7: Entry 1 of 1

File: PGPB

Jun 17, 2004

PGPUB-DOCUMENT-NUMBER: 20040117162

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20040117162 A1

TITLE: Modeling substrate noise coupling using scalable parameters

PUBLICATION-DATE: June 17, 2004

INVENTOR-INFORMATION:

NAME CITY STATE COUNTRY Ozis, Dicle Seattle WA US Mayaram, Kartikeya Corvallis OR US Fiez, Terri Corvallis OR US

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L8: Entry 1 of 12

File: PGPB

Jun 17, 2004

PGPUB-DOCUMENT-NUMBER: 20040117162

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20040117162 A1

TITLE: Modeling substrate noise coupling using scalable parameters

PUBLICATION-DATE: June 17, 2004

INVENTOR-INFORMATION:

CITY NAME STATE COUNTRY Ozis, Dicle Seattle WA US Mayaram, Kartikeya Corvallis OR US Corvallis Fiez, Terri OR US

US-CL-CURRENT: 703/2

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Draw De

2. Document ID: US 20020022951 A1

L8: Entry 2 of 12

File: PGPB Feb 21, 2002

PGPUB-DOCUMENT-NUMBER: 20020022951

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20020022951 A1

TITLE: Method, apparatus and computer program product for determination of noise in

mixed signal systems

PUBLICATION-DATE: February 21, 2002

INVENTOR-INFORMATION:

NAME CITY STATE COUNTRY

Heijningen, Marc VanLeuvenBEBadaroglu, MustafaLeuvenBE

Record List Display Page 2 of 6

Full Title Citation Front Review Classification Date Reference Sequences Attachments Claims KMC Draw De

☐ 3. Document ID: US 20010029601 A1

L8: Entry 3 of 12

File: PGPB

Oct 11, 2001

PGPUB-DOCUMENT-NUMBER: 20010029601

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20010029601 A1

TITLE: Semiconductor device analyzer, method for analyzing/manufacturing semiconductor device, and storage medium storing program for analyzing

semiconductor device

PUBLICATION-DATE: October 11, 2001

INVENTOR-INFORMATION:

NAME CITY STATE COUNTRY.

Kimura, Tomohisa Tokyo JP Okumura, Makiko Kanagawa JP

US-CL-CURRENT: 716/19; 716/4

Full Title Citation Front Review Classification Date Reference Sequences Attachments Claims KWIC Draw. De

☐ 4. Document ID: US 7016820 B2

L8: Entry 4 of 12

File: USPT

Mar 21, 2006

US-PAT-NO: 7016820

DOCUMENT-IDENTIFIER: US 7016820 B2

TITLE: Semiconductor device analyzer, method for analyzing/manufacturing semiconductor device, and storage medium storing program for analyzing

semiconductor device

DATE-ISSUED: March 21, 2006

PRIOR-PUBLICATION:

DOC-ID DATE

US 20010029601 A1 October 11, 2001

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY

Kimura; Tomohisa Tokyo JP Okumura; Makiko Kanagawa JP

US-CL-CURRENT: 703/2; 700/121, 703/14, 716/4

Record List Display Page 3 of 6

Full Title Citation Front Review Classification Date Reference Sequences Attachments Claims KWC Draw De

☐ 5. Document ID: US 6941258 B2

L8: Entry 5 of 12

File: USPT

Sep 6, 2005

US-PAT-NO: 6941258

DOCUMENT-IDENTIFIER: US 6941258 B2

TITLE: Method, apparatus and computer program product for determination of noise in

mixed signal systems

DATE-ISSUED: September 6, 2005

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY

Van Heijningen; MarcLeuvenBEBadaroglu; MustafaLeuvenBE

US-CL-CURRENT: 703/16; 703/14, 703/15, 703/17, 703/2, 716/6

Full Title Citation Front Review Classification Date Reference Section 218 Stackments Claims KWIC Draw De

☐ 6. Document ID: US 6920417 B2

L8: Entry 6 of 12

File: USPT

Jul 19, 2005

US-PAT-NO: 6920417

DOCUMENT-IDENTIFIER: US 6920417 B2

TITLE: Apparatus for modeling IC substrate noise utilizing improved doping profile

access key

DATE-ISSUED: July 19, 2005

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY

Lescot; Jerome D. Grenoble FR Marchand; Bertrand L. Grenoble FR

US-CL-CURRENT: <u>703/13</u>; <u>438/510</u>, <u>703/2</u>

Full Title Citation Front Review Classification Date Reference Seguences Attachments Claims KMC Draw. De

☐ 7. Document ID: US 6895344 B2

L8: Entry 7 of 12

File: USPT

May 17, 2005

US-PAT-NO: 6895344

Record List Display Page 4 of 6

DOCUMENT-IDENTIFIER: US 6895344 B2

TITLE: Extracting resistances for a substrate network

DATE-ISSUED: May 17, 2005

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY

Ramaswamy; Sridhar Plano TX

US-CL-CURRENT: 702/57; 455/3.02, 716/19, 716/6

Full Title Citation Front Review Classification Date Reference Sequences Aux (notified Claims KWC Draw, De

□ 8. Document ID: US 6725185 B2

L8: Entry 8 of 12

File: USPT

Apr 20, 2004

US-PAT-NO: 6725185

DOCUMENT-IDENTIFIER: US 6725185 B2

** See image for <u>Certificate of Correction</u> **

TITLE: Apparatus for modeling IC substrate noise

DATE-ISSUED: April 20, 2004

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY

Clement; Francois J. R. Neuchatel CH

US-CL-CURRENT: 703/14; 438/210, 438/510, 703/2, 716/4

Full Title Citation Front Review Classification Date Reference Sequences Attackments Claims KWC Draw De

9. Document ID: US 6480986 B1

L8: Entry 9 of 12

File: USPT

Nov 12, 2002

US-PAT-NO: 6480986

DOCUMENT-IDENTIFIER: US 6480986 B1

TITLE: IC substrate noise modeling including extracted capacitance for improved

accuracy

DATE-ISSUED: November 12, 2002

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY

Richer; Jean-Michel Voiron FR

Record List Display Page 5 of 6

US-CL-CURRENT: 716/4; 438/510, 716/1

Full Title Citation Front Review Classification Date Reference Sequences Attachments Claims KMC Draw De

☐ 10. Document ID: US 6438733 B1

L8: Entry 10 of 12

File: USPT

Aug 20, 2002

US-PAT-NO: 6438733

DOCUMENT-IDENTIFIER: US 6438733 B1

TITLE: IC substrate noise modeling with improved surface gridding technique

DATE-ISSUED: August 20, 2002

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY

Clement; Fran.cedilla.ois J. R. Neuchatel CH

US-CL-CURRENT: 716/4

Full Title Citation Front Review Classification Date Reference Sequences Placking Claims KWC Draw De

☐ 11. Document ID: US 6291324 B1

L8: Entry 11 of 12

File: USPT

Sep 18, 2001

US-PAT-NO: 6291324

DOCUMENT-IDENTIFIER: US 6291324 B1

TITLE: Method of modeling IC substrate noises utilizing improved doping profile

access

DATE-ISSUED: September 18, 2001

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY

Lescot; Jerome D. Grenoble FR
Marchand; Bertrand L. Grenoble FR

US-CL-CURRENT: 438/510; 438/424

Full Title Citation Front Review Classification Date Reference Sequences Atachments Claims KVMC Draw. De

☐ 12. Document ID: US 6291322 B1

L8: Entry 12 of 12

File: USPT

Sep 18, 2001

US-PAT-NO: 6291322

DOCUMENT-IDENTIFIER: US 6291322 B1

Record List Display Page 6 of 6

** See image for Certificate of Correction **

TITLE: Method for modeling noises in an integrated circuit

DATE-ISSUED: September 18, 2001

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY

Clement; Fran.cedilla.ois J. R. Neuchatel CH

US-CL-CURRENT: 438/510; 438/210

	Bkwd Refs Generat
Term	Documents
SUBSTRATE	815034
SUBSTRATES	335473
MODEL\$	C
MODEL	582924
MODELA	20
MODELAA	3
MODELABBRV	1
MODELABILITIES	1
MODELABILITY	21
MODELABLE	65
MODELABSTRACTION	1
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☐ 1. Document ID: US 20050023656 A1

Using default format because multiple data bases are involved.

L11: Entry 1 of 2

File: PGPB

Feb 3, 2005

PGPUB-DOCUMENT-NUMBER: 20050023656

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20050023656 A1

TITLE: Vertical system integration

PUBLICATION-DATE: February 3, 2005

INVENTOR-INFORMATION:

NAME CITY STATE COUNTRY

Leedy, Glenn J. Saline MI US

US-CL-CURRENT: 257/678; 257/686, 438/106, 438/109

<u>Full Title Citation Front Review Classification Date Reference Sequences Attachments Claims KMC Draw-De</u>

☐ 2. Document ID: US 20040117162 A1

L11: Entry 2 of 2 File: PGPB Jun 17, 2004

PGPUB-DOCUMENT-NUMBER: 20040117162

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20040117162 A1

TITLE: Modeling substrate noise coupling using scalable parameters

PUBLICATION-DATE: June 17, 2004

INVENTOR-INFORMATION:

NAME CITY STATE COUNTRY Ozis, Dicle Seattle WA US Mayaram, Kartikeya Corvallis OR US Fiez, Terri Corvallis OR US